

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 273506US2PCT		SERIAL NO. 538062 New U.S. PCT Application Based on PCT/FR03/02091	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Ulrich BOCKELMANN, et al.		FILING DATE Herewith	
				GROUP			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
/JL/	AA	4,238,757	12/09/80	SCHENCK, John F.			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
/JL/	AO	03/054225	07/03/03	WO(with English abstract)			NO
/JL/	AF	03/052097	06/26/03	WO(with English abstract)			NO
/JL/	AO	00/75276	12/14/00	WO			NO
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
/JL/	AW	SOUTEYRAND, E. et al.: "Direct Detection of the Hybridization of Synthetic Homo-Oligomer DNA Sequences by Field Effect" J. Phys. Chem., vol. 101, pages 2980-2985, 1997. XP-001040796					
/JL/	AX	TSURUTA, Hitoshi et al.: "Detection of the products of polymerase chain reaction by an ELISA system based on an ion sensitive field effect transistor" Journal of Immunological Methods, Vol 176, pages 45-52, 1994. XP009021947					
/JL/	AY	NAKAMURA, M. and YANO, M.: "Online pH, pCO2 and pO2 monitoring system using two-way cyclic pumping of lactate Ringer as a baseline solution" Medical & Biological Engineering & Computing, Vol. 25, pages 45-50, January 1987. XP-001156254					
/JL/	AZ	KIESSLING, Volker et al.: "Extracellular Resistance in Cell Adhesion Measured with a Transistor Probe" Langmuir, Vol. 16, pages 3517-3521, 2000. XP-001040795				<input type="checkbox"/> Additional References sheet(s) attached	
Examiner /Jerry Lin/				Date Considered 02/15/2010			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							